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Application/Control No.	Applicant(s)/Patent under Reexamination	
09/981,019	NAKAMICHI ET AL.	
Examiner	Art Unit	
Bob A. Phunkulh	2661	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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(INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
370/255, 254, 400, 407, 408, 409, (text search)	8/18/2005	ВАР
EAST (Text search)	8/20/2005	ВАР
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